All-In-One Laser Beam Profiling

BeamWave® FIR is a smart instrument providing the highest resolution and dynamic range for wavefront analysis and beam characterization of FIR CW or pulsed sources and laser assemblies from 2 to 16µm.

BeamWave® FIR delivers simultaneously intensity and phase measurements with **unique benefits**:



- All-In-One device for wavefront & intensity measurements
- Complete laser beam characterization in one shot measurement
- Beam propagation analysis
- M², Zernike analysis, MTF, PSF measurements
- · Cost effective, compact & light metrology instrument

BeamWave sensors provide high resolution beam & wavefront analysis

High Resolution Laser Beam Profiling • High-Resolution Wavefront Analysis

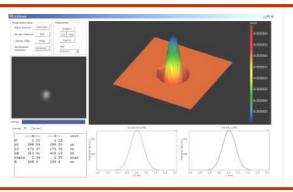
CO²/FIR Laser Beam Profiling • Field Servicing of Laser Systems • Pass/Fail Analysis

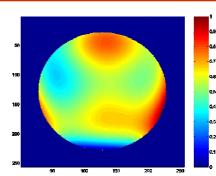
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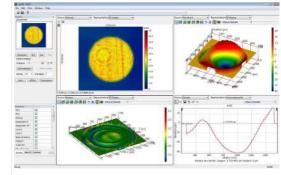
Powered by

Based on the patented Digital Wavefront Technology, GetLase® performs in a remarkably fast and easy way, beam profiling analysis and high resolution wavefront including M^2 , Zernike, MTF and PSF. GetLase® measurements comprehensive tools from automatic acquisition to wavefront display, analysis and reports.

- **Acquisition & Display**
- Automatic Calibration
- Automatic Acquisition
- Exposure time adjustment
- External Auto Trigger Sync
- Live display of 3D high-resolution wavefront Intensity Weighted beam Centroid
- Live display high-resolution intensity image
- Analysis & Measurement
- 2D & 3D Wavefronts
- XY & 3D Beam Profiles
- Major, Minor & Mean Beam Diameters, Axis Auto-Orientation
- Beam Wander Display & Statistics
- Data Export & Report
- Image & Profile Averaging
- User-set rectangular or elliptic regions
- Wavefront data exporting: Matlab, Excel
- User-defined pass/fail criteria
- HTML Compatible Presentation
- Report Editor







Technical Specifications

Wavelength	2 - 16 μm
Pixels	640 x 480
Pixel Pitch	17 μm
Image Area	10.88 x 8.16 mm
Wavefront Measurement Points / lateral resolution	640x480 / 17μm
Sensitivity	0.01 λ
Dynamic Range	1 500 λ
Weight	272 g
Dimensions	61 x 67 x 66 mm
PC Interface	USB 2.0 Windows 7, XP, Vista

Applications

CO²/FIR Laser Beam Profiling

- Single shot complete laser beam characterization
- High-resolution wavefront analysis
- Simultaneous high-resolution phase & intensity
- High precision beam profiling

Field Servicing of Laser Systems

- Easy optics assembly alignment
- Small size instrument
- Easy integration in any optical setup in confined spaces

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